



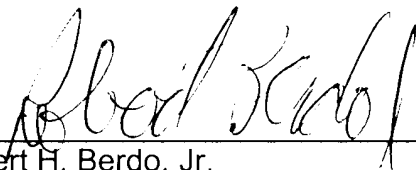
KAN 120D1

**REMARKS**

The specification has been amended to identify sectional views of FIGS. 14 and 20 in the "Brief Description of Drawings" section. No new matter has been added by this amendment to the drawings.

Respectfully submitted,

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Date

  
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**VERSION WITH MARKINGS SHOWING CHANGES MADE**In the specification:

Please delete the paragraph on page 8, lines 17-19, and replace it with the following paragraph.

--FIG. 14A and FIG. 14B are plan views of a wafer to be measured that may be tested by the semiconductor device test apparatus illustrated in FIG. 13;-

Please delete the paragraph on page 9, lines 1-3, and replace it with the following paragraph.

--FIG. 20A and FIG. 20B are plan views of a wafer to be measured that may be tested by the semiconductor device test apparatus illustrated in FIG. 19;--